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FQP3P50

500V P-Channel MOSFET

General Description

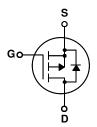
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for electronic lamp ballast based on complimentary half bridge.

Features

- -2.7A, -500V, $R_{DS(on)}$ = 4.9 Ω @V_{GS} = -10 V Low gate charge (typical 18 nC)
- Low Crss (typical 9.5 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25 °C unless otherwise noted

Symbol	Parameter		FQP3P50	Units	
V _{DSS}	Drain-Source Voltage		-500	V	
I _D	Drain Current - Continuous (T _C = 25°	C)	-2.7	Α	
	- Continuous (T _C = 100 °C)		-1.71	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	-10.8	Α	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	250	mJ	
I _{AR}	Avalanche Current	(Note 1)	-2.7	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	8.5	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns	
P_{D}	Power Dissipation (T _C = 25 °C)		85	W	
	- Derate above 25 ℃		0.68	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	∞	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	℃	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.47	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	%C\M

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-500			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = -250 μA, Referenced to 25 ℃		0.42		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -500 V, V _{GS} = 0 V			-1	μΑ
		V _{DS} = -400 V, T _C = 125 ℃			-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = -250 μA	-3.0		-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -1.35 A		3.9	4.9	Ω
9 _{FS}	Forward Transconductance	V _{DS} = -50 V, I _D = -1.35 A (Note 4)		2.35		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		510 70	90	pF pF
C _{rss}	Reverse Transfer Capacitance			9.5	12	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = -250 V, I _D = -2.7 A,		12	35	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		56	120	ns
t _{d(off)}	Turn-Off Delay Time			35	80	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		45	100	ns
Q_g	Total Gate Charge	$V_{DS} = -400 \text{ V}, I_{D} = -2.7 \text{ A},$		18	23	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -10 V		3.6		nC
Q_{gd}	Gate-Drain Charge	(Note 4, 5)		9.2		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
Is	Maximum Continuous Drain-Source Diode Forward Current				-2.7	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	orward Current			-10.8	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -2.7 \text{ A}$			-5.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = -2.7 \text{ A},$		270		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		1.5		μС

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 62mH, I_{AS} = -2.7A, V_{DD} = -50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C 3. I_{SD} $^{\circ}$ < -2.7A, didt $^{\circ}$ 200A/µs, V_{DD} $^{\circ}$ 8 W_{DSS}, Starting T_J = 25 $^{\circ}$ C 4. Pulse Test : Pulse width $^{\circ}$ 300µs, Duty cycle $^{\circ}$ 2% 5. Essentially independent of operating temperature

Typical Characteristics

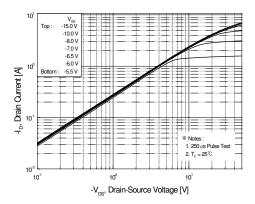


Figure 1. On-Region Characteristics

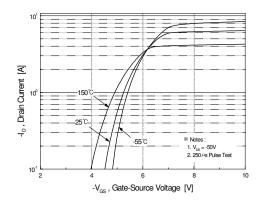


Figure 2. Transfer Characteristics

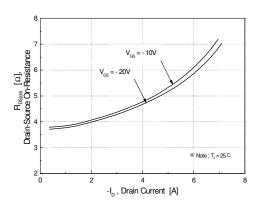


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

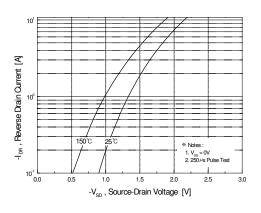


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

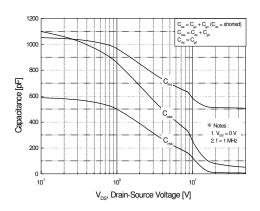


Figure 5. Capacitance Characteristics

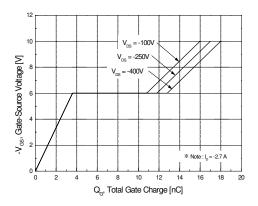
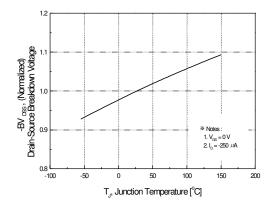


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)



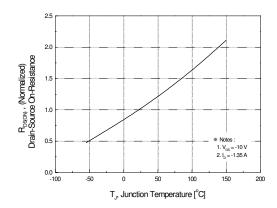
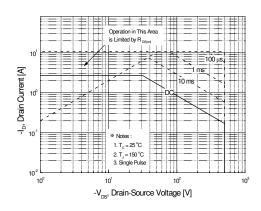


Figure 7. Breakdown Voltage Variation vs. Temperature





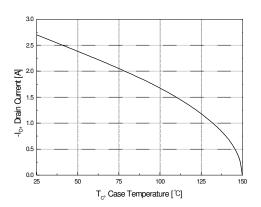


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

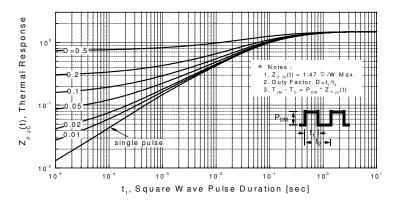
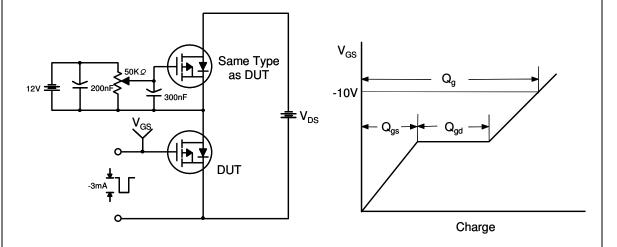


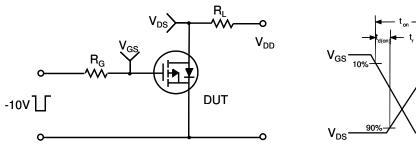
Figure 11. Transient Thermal Response Curve

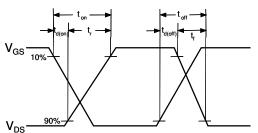
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Gate Charge Test Circuit & Waveform

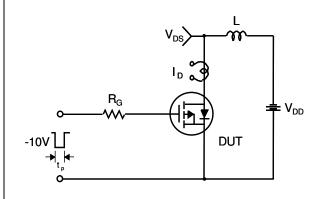


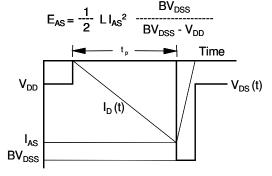
Resistive Switching Test Circuit & Waveforms



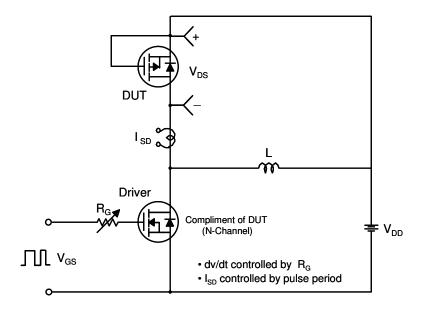


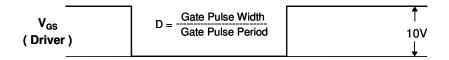
Unclamped Inductive Switching Test Circuit & Waveforms



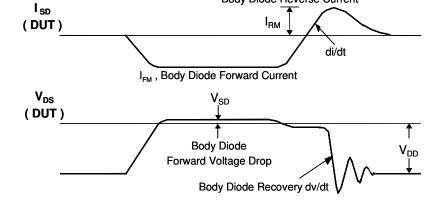


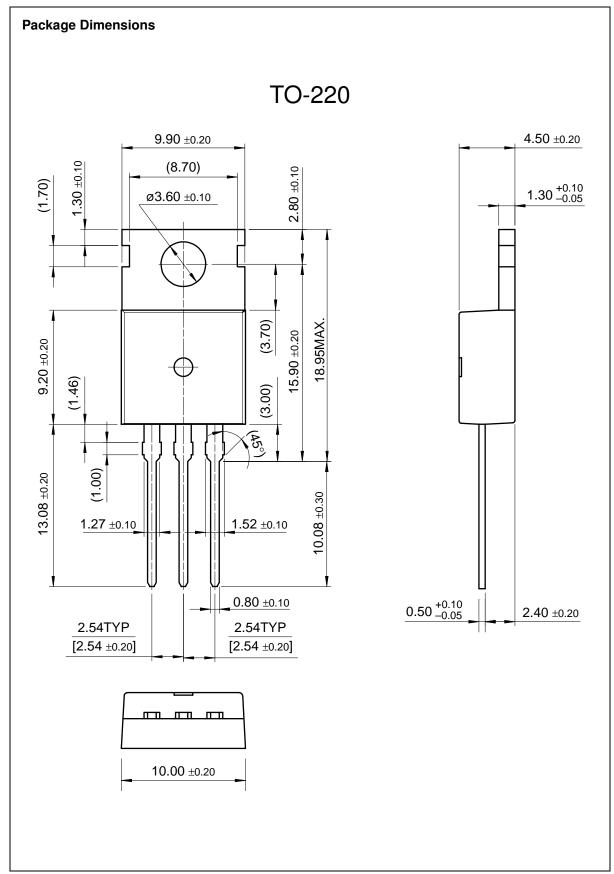
Peak Diode Recovery dv/dt Test Circuit & Waveforms





Body Diode Reverse Current





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